

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/785,294	<b>Applicant(s)/Patent under Reexamination</b>  LEE, YEOU-CHING
	<b>Examiner</b>  EDMUND H. LEE	<b>Art Unit</b>  1732

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner